# Tracking Regulator/Line **Driver** - Micropower, **Low Dropout**

### 70 mA

The NCV8184 is a monolithic integrated low dropout tracking voltage regulator designed to provide an adjustable buffered output voltage that closely tracks (±3.0 mV) the reference input.

The part can be used in automotive applications with remote sensors, or any situation where it is necessary to isolate the output of your regulator.

The NCV8184 also enables the user to bestow a quick upgrade to their module when added current is needed, and the existing regulator cannot provide.

The versatility of this part also enables it to be used as a high-side driver.

#### **Features**

- 70 mA Source Capability
- Output Tracks within ±3.0 mV
- Low Input Voltage Tracking Performance (Works Down to  $V_{REF} = 2.1 \text{ V}$ )
- Low Dropout (0.35 V Typ. @ 50 mA)
- Low Quiescent Current
- Thermal Shutdown
- Wide Operating Range
- Internally Fused Leads in SOIC-8 Package
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

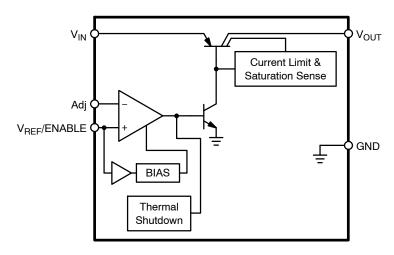


Figure 1. Block Diagram

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SOIC-8 **D SUFFIX CASE 751** 

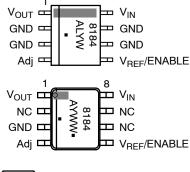
SOIC-8 EP **PD SUFFIX** CASE 751AC

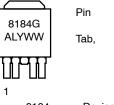




**DPAK 5-LEAD DT SUFFIX** CASE 175AA

#### **PIN CONNECTIONS AND MARKING DIAGRAMS**





2. V<sub>OUT</sub> 3. GND

4. Adj

1. V<sub>IN</sub>

5. V<sub>REF</sub>/ENABLE

8184 = Device Code = Assembly Location Α

= Wafer Lot = Year = Work Week W, WW = Pb-Free Package

#### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 17 of this data sheet.

#### **MAXIMUM RATINGS**

Ra	ting	Value	Unit
Storage Temperature		-65 to 150	°C
Supply Voltage Range (Continuous)		–15 to 45	V
Supply Voltage Operating Range		4.0 to 42	V
Peak Transient Voltage (V <sub>IN</sub> = 14 V, Load Du	mp Transient = 31 V)	45	V
Voltage Range (V <sub>OUT</sub> , Adj)		-3.0 to 45	V
Voltage Range (V <sub>REF</sub> /ENABLE)		-0.3 to 45	V
Maximum Junction Temperature		150	°C
ESD Capability	Human Body Model Machine Model Charge Device Model	2.5 200 1000	kV V V
Lead Temperature Soldering:	Reflow: (SMD styles only) (Note 1)	240 peak 260 peak (Pb-Free) (Note 2)	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. 60 second maximum above 183°C.
- 2.  $-5^{\circ}\text{C}$  /  $+0^{\circ}\text{C}$  Allowable Conditions, applies to both Pb and Pb–Free devices.

### THERMAL CHARACTERISTICS See Package Thermal Data Section (Page 8)

 $\begin{array}{l} \textbf{ELECTRICAL CHARACTERISTICS} \quad \text{($V_{IN}=14$ V; $V_{REF}/ENABLE>2.1$ V; $-40^{\circ}C < T_{J} < +150^{\circ}C; $C_{OUT}=1.0$ $\mu F$; $I_{OUT}=1.0$ mA; $Adj=V_{OUT}$, $C_{OUT-ESR}=1.0$ $\Omega$, unless otherwise specified.) } \end{array}$ 

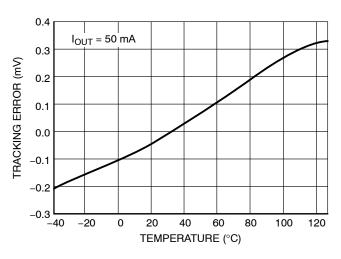
Parameter	Test Conditions	Min	Тур	Max	Unit
REGULATOR OUTPUT	·		•	•	
V <sub>REF</sub> /ENABLE – V <sub>OUT</sub> V <sub>OUT</sub> Tracking Error	5.7 V $\leq$ V <sub>IN</sub> $\leq$ 26 V, 100 $\mu$ A $\leq$ I <sub>OUT</sub> $\leq$ 60 mA 2.1 V $\leq$ V <sub>REF</sub> /ENABLE $\leq$ (V <sub>IN</sub> $-$ 600 mV)	-3.0	-	3.0	mV
Dropout Voltage (V <sub>IN</sub> – V <sub>OUT</sub> )	$\begin{split} I_{OUT} &= 100 \ \mu\text{A} \\ I_{OUT} &= 5.0 \ \text{mA} \\ I_{OUT} &= 60 \ \text{mA} \end{split}$	- - -	100 250 350	150 500 600	mV mV mV
Line Regulation	5.7 V ≤ V <sub>IN</sub> ≤ 26 V, V <sub>REF</sub> /ENABLE = 5.0 V	-	-	3.0	mV
Load Regulation	100 $\mu$ A $\leq$ I <sub>OUT</sub> $\leq$ 60 mA, V <sub>REF</sub> /ENABLE = 5.0 V	-	-	3.0	mV
Adj Input Bias Current	V <sub>REF</sub> /ENABLE = 5.0 V	_	0.2	6.0	μΑ
Current Limit	V <sub>IN</sub> = 14 V, V <sub>REF</sub> = 5.0 V, V <sub>OUT</sub> = 90% of V <sub>REF</sub> (Note 3)	70	-	225	mA
Quiescent Current (I <sub>IN</sub> – I <sub>OUT</sub> )	$V_{IN}$ = 12 V, $I_{OUT}$ = 60 mA $V_{IN}$ = 12 V, $I_{OUT}$ = 100 $\mu$ A $V_{IN}$ = 12 V, $V_{REF}$ /ENABLE = 0 V	- - -	5.0 50 -	7.0 70 20	mA μA μA
Ripple Rejection	$f = 120 \text{ Hz}, I_{OUT} = 60 \text{ mA}, 6.0 \text{ V} \le V_{IN} \le 26 \text{ V}$	60	-	-	dB
Thermal Shutdown	Guaranteed by Design	150	180	210	°C
V <sub>REF</sub> /ENABLE	•	•	•	•	•
Enable Voltage	-	8.0	-	2.1	V
Input Bias Current	V <sub>REF</sub> /ENABLE = 5.0 V	_	0.2	3.0	μΑ

<sup>3.</sup> V<sub>OUT</sub> connected to Adj lead.

#### **PACKAGE PIN DESCRIPTION**

Package Lead Number				
SOIC-8 EPAD	SOIC-8 EPAD SOIC-8 DPAK, 5-LEAD		Lead Symbol	Function
8	8	1	V <sub>IN</sub>	Battery supply input voltage.
1	1	2	V <sub>OUT</sub>	Regulated output.
3, EPAD	2, 3, 6, 7	Tab, 3	GND	Ground.
4	4	4	Adj	Adjust lead, noninverting input.
5	5	5	V <sub>REF</sub> /ENABLE	Reference voltage and ENABLE input.
2, 6, 7	-	-	NC	No Connection. PCB traces allowed.

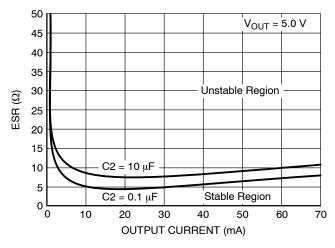
#### TYPICAL PERFORMANCE CHARACTERISTICS



8.0 TRACKING ERROR (mV) 0.6 +125°C 0.4 0.2 +25°C 0.0 -0.2 -40°C -0.4 -0.6 30 70 20 40 50 60 **OUTPUT CURRENT (mA)** 

Figure 2. Tracking Error vs. Temperature

Figure 3. Tracking Error vs. Output Current



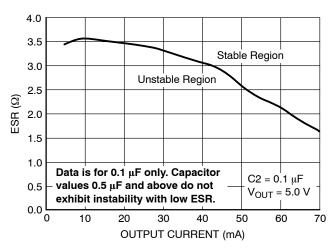
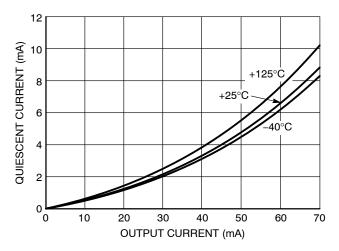


Figure 4. Output Stability with Capacitor Change

Figure 5. Output Stability with 0.1  $\mu\text{F}$  at Low ESR



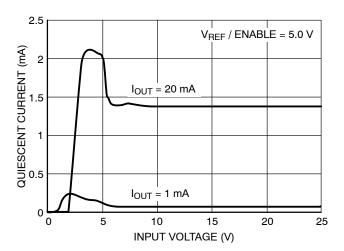


Figure 6. Quiescent Current vs. Output Current

Figure 7. Quiescent Current vs. Input Voltage

#### TYPICAL PERFORMANCE CHARACTERISTICS

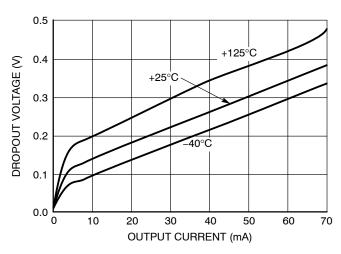
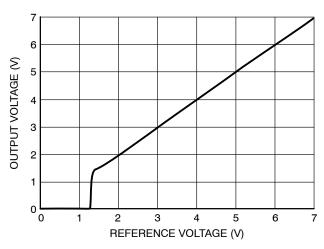


Figure 8. Dropout Voltage vs. Output Current

Figure 9. Output Voltage vs. Input Voltage



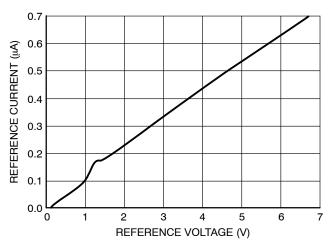


Figure 10. Output Voltage vs. Reference Voltage

Figure 11. Reference Current vs. Reference Voltage

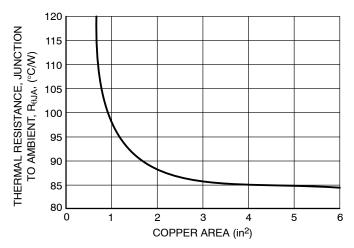


Figure 12. SOIC-8,  $\theta$ JA as a Function of the Pad Copper Area (2.0 oz. Cu Thickness), Board Material = 0.0625 G-10/R-4

#### **CIRCUIT DESCRIPTION**

#### **ENABLE Function**

By pulling the  $V_{REF}$ /ENABLE lead below 0.8 V, (see Figure 16 or Figure 17), the IC is disabled and enters a sleep state where the device draws less than 20  $\mu$ A from supply. When the  $V_{REF}$ /ENABLE lead is greater than 2.1 V,  $V_{OUT}$  tracks the  $V_{REF}$ /ENABLE lead normally.

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Figure 13. Tracking Regulator at the Same Voltage

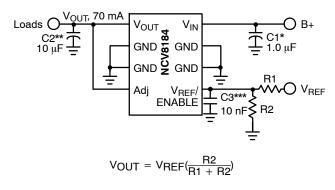


Figure 15. Tracking Regulator at Lower Voltages

#### **Output Voltage**

The output is capable of supplying 70 mA to the load while configured as a similar (Figure 13), lower (Figure 15), or higher (Figure 14) voltage as the reference lead. The Adj lead acts as the inverting terminal of the op amp and the  $V_{REF}$  lead as the non-inverting.

The device can also be configured as a high-side driver as displayed in Figure 18.

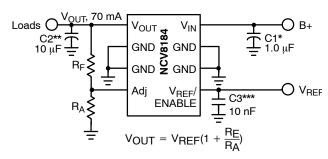


Figure 14. Tracking Regulator at Higher Voltages

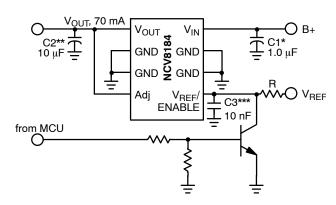


Figure 16. Tracking Regulator with ENABLE Circuit

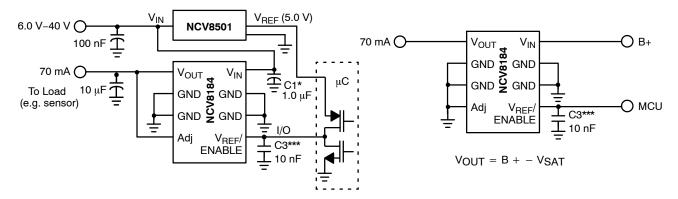


Figure 17. Alternative ENABLE Circuit

Figure 18. High-Side Driver

- \*C1 is required if the regulator is far from the power source filter. In case of power supply generates voltage ripple (e.g. DC-DC converter) a passive low pass filter with C1 value at least 1  $\mu$ F is required to suppress the ripple. The filter should be designed according to particular operating conditions and verified in the application.
- \*\* C2 is required for stability.
- \*\*\* C3 is recommended for EMC susceptibility

#### **APPLICATION NOTES**

#### **VOUT Short to Battery**

The NCV8184 will survive a short to battery when hooked up the conventional way as shown in Figure 19. No damage to the part will occur. The part also endures a short to battery when powered by an isolated supply at a lower voltage as in Figure 20. In this case the NCV8184 supply input voltage is set at 7.0 V when a short to battery (14 V typical) occurs on  $V_{OUT}$  which normally runs at 5.0 V. The current into the device (ammeter in Figure 20) will draw additional current as displayed in Figure 21.

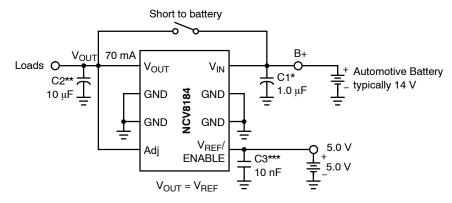


Figure 19.

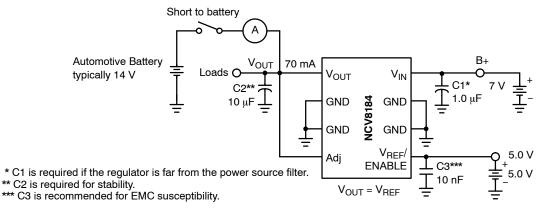


Figure 20.

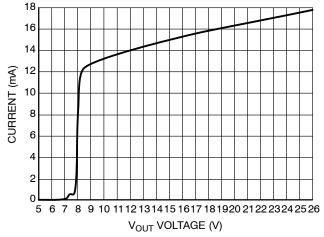


Figure 21. VOUT Short to Battery

#### **Switched Application**

The NCV8184 has been designed for use in systems where the reference voltage on the  $V_{REF}/ENABLE$  pin is continuously on. Typically, the current into the  $V_{REF}/ENABLE$  pin will be less than 1.0  $\mu A$  when the voltage on the  $V_{IN}$  pin (usually the ignition line) has been switched out ( $V_{IN}$  can be at high impedance or at ground.) Reference Figure 22.

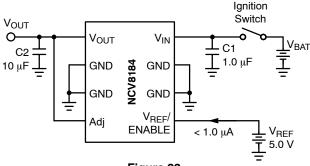


Figure 22.

#### **External Capacitors**

The output capacitor for the NCV8184 is required for stability. Without it, the regulator output will oscillate. Actual size and type may vary depending upon the application load and temperature range. Capacitor effective series resistance (ESR) is also a factor in the IC stability. Worst–case is determined at the minimum ambient temperature and maximum load expected.

The output capacitor can be increased in size to any desired value above the minimum. One possible purpose of this would be to maintain the output voltage during brief conditions of negative input transients that might be characteristic of a particular system.

The capacitor must also be rated at all ambient temperatures expected in the system. To maintain regulator stability down to  $-40^{\circ}$ C, a capacitor rated at that temperature must be used.

More information on capacitor selection for SMART REGULATOR®s is available in the SMART REGULATOR application note, "Compensation for Linear Regulators," document number SR003AN/D, available through our website at http://www.onsemi.com.

# Calculating Power Dissipation in a Single Output Linear Regulator

The maximum power dissipation for a single output regulator (Figure 23) is:

$$\begin{split} PD(max) &= \{V_{IN}(max) - V_{OUT}(min)\} \, I_{OUT}(max) \\ &+ V_{IN}(max)I_{Q} \end{split} \tag{eq. 1}$$

where:

 $V_{IN(max)}$  is the maximum input voltage,

V<sub>OUT(min)</sub> is the minimum output voltage,

 $I_{OUT(max)}$  is the maximum output current, for the application,and

 $I_Q$  is the quiescent current the regulator consumes at  $I_{OUT(max)}. \label{eq:lower}$ 

Once the value of PD(max) is known, the maximum permissible value of  $R_{\theta JA}$  can be calculated:

$$R_{\theta JA} = \frac{150^{\circ}C - T_{A}}{P_{D}} \qquad (eq. 2)$$

The value of  $R_{\theta JA}$  can then be compared with those in the Package Thermal Data Section of the data sheet. Those packages with  $R_{\theta JA}$ 's less than the calculated value in equation 2 will keep the die temperature below 150°C.

In some cases, none of the packages will be sufficient to dissipate the heat generated by the IC, and an external heat sink will be required.

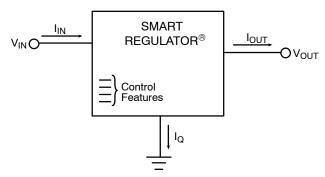


Figure 23. Single Output Regulator with Key Performance Parameters Labeled

#### **Heatsinks**

A heatsink effectively increases the surface area of the package to improve the flow of heat away from the IC and into the surrounding air.

Each material in the heat flow path between the IC and the outside environment will have a thermal resistance. Like series electrical resistances, these resistances are summed to determine the value of  $R_{\theta IA}$ .

$$R_{\theta}JA = R_{\theta}JC + R_{\theta}CS + R_{\theta}SA$$
 (eq. 3)

where:

 $R_{\theta IC}$  = the junction-to-case thermal resistance,

 $R_{\theta CS}$  = the case-to-heatsink thermal resistance, and

 $R_{\theta SA}$  = the heatsink-to-ambient thermal resistance.

 $R_{\theta JC}$  appears in the package section of the data sheet. Like  $R_{\theta JA}$ , it is a function of package type.  $R_{\theta CS}$  and  $R_{\theta SA}$  are functions of the package type, heatsink and the interface between them. These values appear in heat sink data sheets of heatsink manufacturers.

### PACKAGE THERMAL DATA

Parameter	Conditions Typical Value				
	100 mm <sup>2</sup> Spreader Board 645 mm <sup>2</sup> Spreader Board			eader Board	
SOIC-8 Package	1 oz	2 oz	1 oz	2 oz	1
Junction-to-Pin 6 (Ψ-JL6, Ψ <sub>JL6</sub> )	53	51	50	47	°C/W
Junction-to-Ambient ( $R_{\theta JA}$ , $\theta_{JA}$ )	151	135	111	100	°C/W

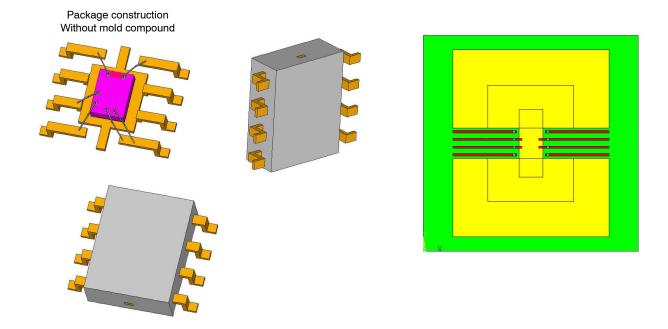


Figure 24. PCB Layout and Package Construction for Simulation

Table 1. SOIC-8 THERMAL RC NETWORK MODELS\*

Сор	per Area (1 oz thi	ick)	100 mm <sup>2</sup>	645 mm <sup>2</sup>		100 mm <sup>2</sup>	645 mm <sup>2</sup>	
			Cauer	Network	Foster Network			
			100 mm <sup>2</sup>	645 mm <sup>2</sup>	Units	Tau	Tau	Units
C_C1	Junction	Gnd	0.0000015	0.0000015	W-s/C	1.00E-06	1.00E-06	sec
C_C2	node1	Gnd	0.0000059	0.0000059	W-s/C	1.00E-05	1.00E-05	sec
C_C3	node2	Gnd	0.0000171	0.0000171	W-s/C	1.00E-04	1.00E-04	sec
C_C4	node3	Gnd	0.0001340	0.0001340	W-s/C	1.76E-04	1.76E-04	sec
C_C5	node4	Gnd	0.0001322	0.0001323	W-s/C	0.0010	0.0010	sec
C_C6	node5	Gnd	0.0010797	0.0010811	W-s/C	0.008	0.008	sec
C_C7	node6	Gnd	0.0087127	0.0087918	W-s/C	0.150	0.150	sec
C_C8	node7	Gnd	0.0863882	0.0950421	W-s/C	3.00	3.00	sec
C_C9	node8	Gnd	0.3109255	1.0127094	W-s/C	8.96	5.15	sec
C_C10	node9	Gnd	0.8359004	1.5167041	W-s/C	52.5	68.4	sec
			100 mm <sup>2</sup>	645 mm <sup>2</sup>		R's	R's	
R_R1	Junction	node1	0.8380955	0.8380935	°C/W	0.49519	0.49519	°C/W
R_R2	node1	node2	1.9719907	1.9719679	°C/W	1.070738	1.070738	°C/W
R_R3	node2	node3	5.0213740	5.0211819	°C/W	3.385971	3.385971	°C/W
R_R4	node3	node4	3.1295806	3.1288061	°C/W	1.617537	1.617537	°C/W
R_R5	node4	node5	3.2483544	3.2468794	°C/W	5.10	5.10	°C/W
R_R6	node5	node6	6.5922506	6.5781209	°C/W	7.00	7.00	°C/W
R_R7	node6	node7	16.5499898	16.2818051	°C/W	15.00	15.00	°C/W
R_R8	node7	node8	45.3838437	34.7292748	°C/W	20.00	20.00	°C/W
R_R9	node8	node9	32.8928798	7.6862725	°C/W	28.19863	16.67727	°C/W
R_R10	node9	gnd	37.5059686	24.4060143	°C/W	71.26626	33.54171	°C/W

<sup>\*</sup>Bold face items in the tables above represent the package without the external thermal system.

The Cauer networks generally have physical significance and may be divided between nodes to separate thermal behavior due to one portion of the network from another. The Foster networks, though when sorted by time constant (as above) bear a rough correlation with the Cauer networks, are really only convenient mathematical models. Cauer networks can be easily implemented using circuit simulating

tools, whereas Foster networks may be more easily implemented using mathematical tools (for instance, in a spreadsheet program), according to the following formula:

$$R(t) = \sum_{i=1}^{n} R_i \left( 1 - e^{-t/tau_i} \right)$$

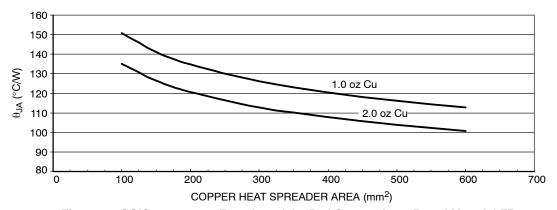


Figure 25. SOIC–8,  $\theta_{\mbox{\scriptsize JA}}$  as a Function of the Pad Copper Area, Board Material FR4

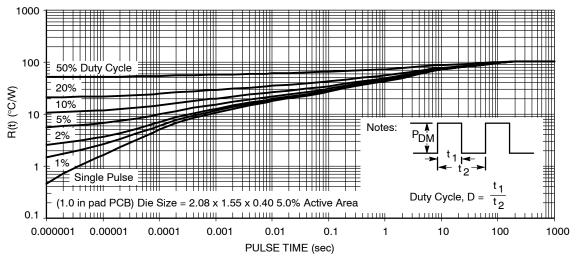


Figure 26. SOIC-8 Thermal Duty Cycle Curves on 1.0 in Spreader Test Board, 1.0 oz Cu

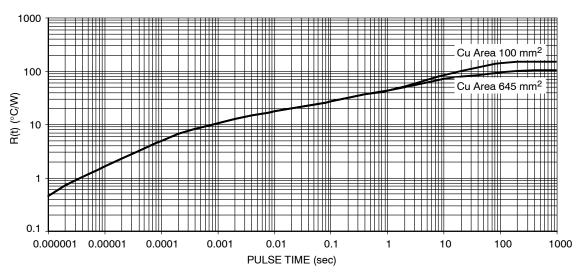


Figure 27. SOIC-8 Single Pulse Heating Curve

### PACKAGE THERMAL DATA

Parameter	Conditions Typical Value				
	100 mm <sup>2</sup> Spreader Board 645 mm <sup>2</sup> Spreader Board			oreader Board	
SOIC-8 EP Package	1 oz	2 oz	1 oz	2 oz	
Junction-to-Board (Ψ-JB, Ψ <sub>JB</sub> )	26	26	26	25	°C/W
Junction-to-Pin 6 (tab) (Ψ-JL6, Ψ <sub>JL6</sub> )	48	45	37	34	°C/W
Junction-to-Ambient (R $_{\theta JA}, \theta_{JA}$ )	140	123	88	78	°C/W

Figure 28. PCB Layout and Package Construction for Simulation

Table 2. SOIC-8 EP THERMAL RC NETWORK MODELS\*

Drain (	Copper Area (1 oz	thick)	100 mm <sup>2</sup>	645 mm <sup>2</sup>		100 mm <sup>2</sup>	645 mm <sup>2</sup>	
(S	(SPICE Deck Format)		at) Cauer Network		Foster Network			
C_C1	Junction	Gnd	100 mm <sup>2</sup> 0.0000015	645 mm <sup>2</sup> 0.0000015	<b>Units</b> W-s/C	Tau 1.00E-06	Tau 1.00E-06	Units sec
C_C2	node1	Gnd	0.0000059	0.0000059	W-s/C	1.00E-05	1.00E-05	sec
C_C3	node2	Gnd	0.0000171	0.0000172	W-s/C	1.00E-04	1.00E-04	sec
C_C4	node3	Gnd	0.0001359	0.0001360	W-s/C	1.76E-04	1.76E-04	sec
C_C5	node4	Gnd	0.0001349	0.0001352	W-s/C	0.0010	0.0010	sec
C_C6	node5	Gnd	0.0011157	0.0011253	W-s/C	0.008	0.008	sec
C_C7	node6	Gnd	0.0110409	0.0118562	W-s/C	0.150	0.150	sec
C_C8	node7	Gnd	0.0963225	0.2080891	W-s/C	3.00	3.00	sec
C_C9	node8	Gnd	0.3406538	1.1005982	W-s/C	9.11	5.12	sec
C_C10	node9	Gnd	0.9202956	0.8512155	W-s/C	52.1	68.6	sec
			100 mm <sup>2</sup>	645 mm <sup>2</sup>		R's	R's	
R_R1	Junction	node1	0.8378620	0.8378491	°C/W	0.49519	0.49519	°C/W
R_R2	node1	node2	1.9693564	1.9692100	°C/W	1.070738	1.070738	°C/W
R_R3	node2	node3	5.0005397	4.9993083	°C/W	3.385971	3.385971	°C/W
R_R4	node3	node4	3.0695514	3.0646169	°C/W	1.617537	1.617537	°C/W
R_R5	node4	node5	3.1989711	3.1895109	°C/W	5.030483	5.030483	°C/W
R_R6	node5	node6	6.2274239	6.1397875	°C/W	7.00	7.00	°C/W
R_R7	node6	node7	13.5796441	11.9712961	°C/W	12.00	12.00	°C/W
R_R8	node7	node8	40.4842477	18.5111622	°C/W	17.676107	7.880592	°C/W
R_R9	node8	node9	30.5112160	10.0330297	°C/W	25.169021	8.550583	°C/W
R_R10	node9	gnd	33.6034987	27.3017101	°C/W	65.037264	40.98639	°C/W

<sup>\*</sup>Bold face items in the tables above represent the package without the external thermal system.

The Cauer networks generally have physical significance and may be divided between nodes to separate thermal behavior due to one portion of the network from another. The Foster networks, though when sorted by time constant (as above) bear a rough correlation with the Cauer networks, are really only convenient mathematical models. Cauer networks can be easily implemented using circuit simulating

tools, whereas Foster networks may be more easily implemented using mathematical tools (for instance, in a spreadsheet program), according to the following formula:

$$R(t) = \sum_{i=1}^{n} R_i \left( 1 - e^{-t/tau_i} \right)$$

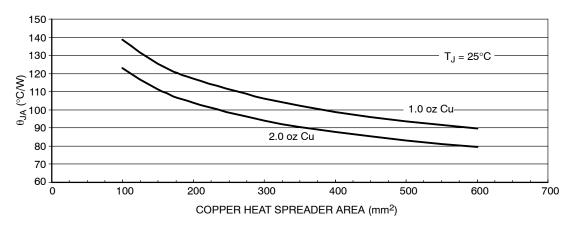


Figure 29. SOIC–8 Exposed Pad,  $\theta_{JA}$  as a Function of the Pad Copper Area, Board Material FR4

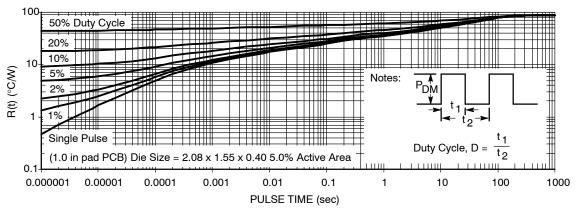


Figure 30. SOIC-8 Exposed Pad Thermal Duty Cycle Curves on 1.0 in Spreader Test Board, 1.0 oz Cu

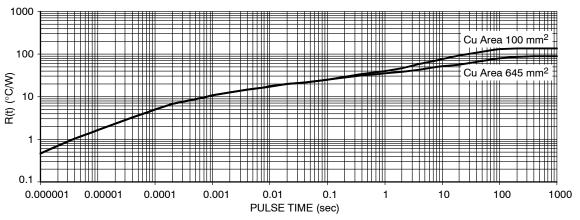


Figure 31. SOIC-8 Exposed Pad Single Pulse Heating Curve

### **PACKAGE THERMAL DATA**

Parameter	Conditions Typical Value				
	100 mm <sup>2</sup> Spi	eader Board	645 mm <sup>2</sup> S <sub>l</sub>		
DPAK 5-LEAD Package	1 oz	2 oz	1 oz	2 oz	
Junction-to-Board-top (Ψ-JB, Ψ <sub>JB</sub> )	18	18	17	16	°C/W
Junction-to-Pin 3 (tab) (Ψ-JL3, Ψ <sub>JL3</sub> )	16	16	16	16	°C/W
Junction-to-Ambient (R $_{\theta JA}, \theta_{JA}$ )	87	77	62	55	°C/W

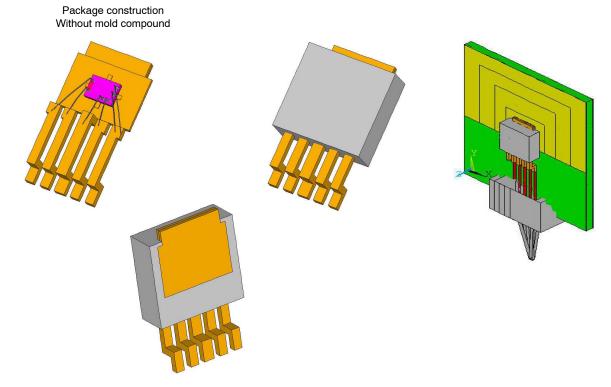


Figure 32. PCB Layout and Package Construction for Simulation

Table 3. DPAK 5-LEAD THERMAL RC NETWORK MODELS\*

Drain (	Copper Area (1 oz	thick)	100 mm <sup>2</sup>	645 mm <sup>2</sup>		100 mm <sup>2</sup>	645 mm <sup>2</sup>	
(S	(SPICE Deck Format)		Cauer Network		Foster Network			
			100 mm <sup>2</sup>	645 mm <sup>2</sup>	Units	Tau	Tau	Units
C_C1	Junction	Gnd	0.0000016	0.0000016	W-s/C	1.00E-06	1.00E-06	sec
C_C2	node1	Gnd	0.0000060	0.0000060	W-s/C	1.00E-05	1.00E-05	sec
C_C3	node2	Gnd	0.0000177	0.0000177	W-s/C	1.00E-04	1.00E-04	sec
C_C4	node3	Gnd	0.0001586	0.0001587	W-s/C	1.76E-04	1.76E-04	sec
C_C5	node4	Gnd	0.0001927	0.0001931	W-s/C	0.0010	0.0010	sec
C_C6	node5	Gnd	0.0056684	0.0058019	W-s/C	0.030	0.030	sec
C_C7	node6	Gnd	0.0832719	0.1225791	W-s/C	0.285	0.299	sec
C_C8	node7	Gnd	0.1125429	0.3555671	W-s/C	3.00	3.00	sec
C_C9	node8	Gnd	0.5161495	1.2959188	W-s/C	9.03	11.80	sec
C_C10	node9	Gnd	1.4600223	1.8396650	W-s/C	55.2	79.0	sec
			100 mm <sup>2</sup>	645 mm <sup>2</sup>		R's	R's	
R_R1	Junction	node1	0.8287213	0.8287120	°C/W	0.490938	0.490938	°C/W
R_R2	node1	node2	1.9304163	1.9303119	°C/W	1.061544	1.061544	°C/W
R_R3	node2	node3	4.7751915	4.7743247	°C/W	3.356895	3.356895	°C/W
R_R4	node3	node4	2.3736457	2.3705112	°C/W	1.606314	1.606314	°C/W
R_R5	node4	node5	2.0679537	2.0623650	°C/W	5.00	5.00	°C/W
R_R6	node5	node6	5.3364094	5.1102633	°C/W	5.00	5.00	°C/W
R_R7	node6	node7	6.0331860	3.2428679	°C/W	2.00	2.00	°C/W
R_R8	node7	node8	22.7616126	8.6995800	°C/W	9.147005	5.071663	°C/W
R_R9	node8	node9	17.9894079	16.1165074	°C/W	17.23178	3.646957	°C/W
R_R10	node9	gnd	22.7199543	16.7871407	°C/W	41.92202	34.68827	°C/W

<sup>\*</sup>Bold face items in the tables above represent the package without the external thermal system.

The Cauer networks generally have physical significance and may be divided between nodes to separate thermal behavior due to one portion of the network from another. The Foster networks, though when sorted by time constant (as above) bear a rough correlation with the Cauer networks, are really only convenient mathematical models. Cauer networks can be easily implemented using circuit simulating

tools, whereas Foster networks may be more easily implemented using mathematical tools (for instance, in a spreadsheet program), according to the following formula:

$$R(t) = \sum_{i=1}^{n} R_i \left(1 - e^{-t/tau_i}\right)$$

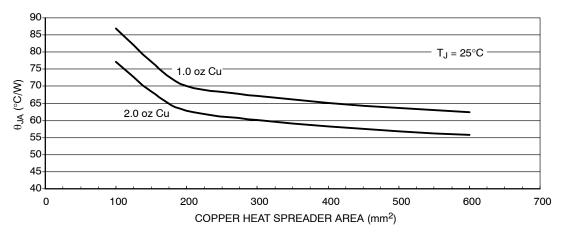


Figure 33. DPAK 5–Lead,  $\theta_{JA}$  as a Function of the Pad Copper Area, Board Material FR4

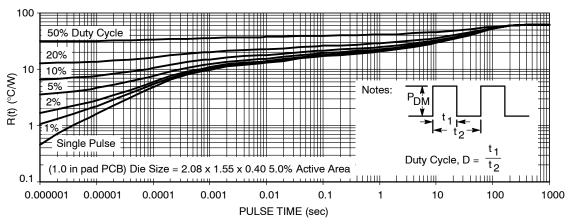


Figure 34. DPAK 5-Lead Thermal Duty Cycle Curves on 1.0 in Spreader Test Board, 1.0 oz Cu

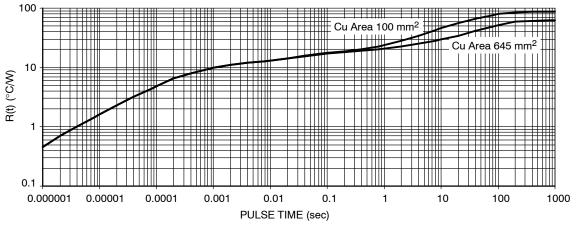


Figure 35. DPAK 5-Lead Single Pulse Heating Curve

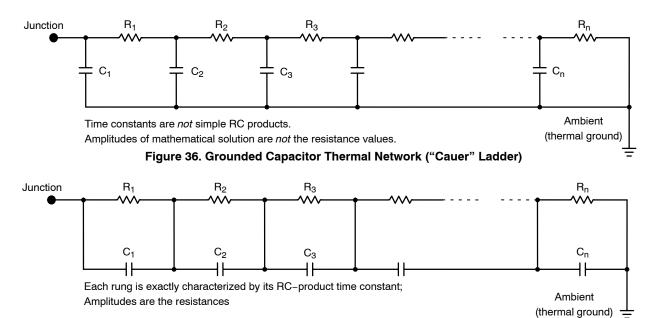


Figure 37. Non-Grounded Capacitor Thermal Ladder ("Foster" Ladder)

#### **ORDERING INFORMATION**

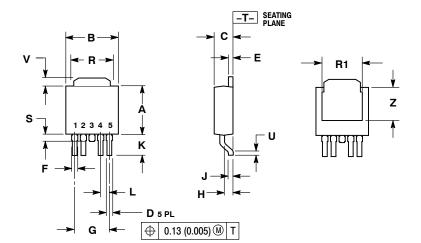
Device Order Number	Package Type	Shipping <sup>†</sup>
NCV8184DG	SOIC-8 (Pb-Free)	98 Units / Tube
NCV8184DR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel
NCV8184DTRKG	DPAK (Pb-Free)	2500 / Tape & Reel
NCV8184PDG	SOIC-8 epad (Pb-Free)	98 Units / Tube
NCV8184PDR2G	SOIC-8 epad (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



#### DPAK-5, CENTER LEAD CROP CASE 175AA **ISSUE B**

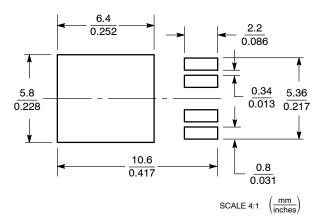
**DATE 15 MAY 2014** 



- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: INCH.

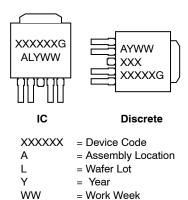
	INC	HES	MILLIM	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.235	0.245	5.97	6.22	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.020	0.028	0.51	0.71	
E	0.018	0.023	0.46	0.58	
F	0.024	0.032	0.61	0.81	
G	0.180	BSC	4.56 BSC		
Н	0.034	0.040	0.87	1.01	
J	0.018	0.023	0.46	0.58	
K	0.102	0.114	2.60	2.89	
L	0.045	BSC	1.14	BSC	
R	0.170	0.190	4.32	4.83	
R1	0.185	0.210	4.70	5.33	
S	0.025	0.040	0.63	1.01	
U	0.020		0.51		
٧	0.035	0.050	0.89	1.27	
Z	0.155	0.170	3.93	4.32	

#### **RECOMMENDED** SOLDERING FOOTPRINT\*



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **GENERIC MARKING DIAGRAMS\***



\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

= Pb-Free Package

DOCUMENT NUMBER:	98AON12855D	Electronic versions are uncontrolled except when accessed directly from the Document Reposi Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.				
DESCRIPTION:	DPAK-5 CENTER LEAD C	ROP	PAGE 1 OF 1			

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SOIC-8 NB CASE 751-07 **ISSUE AK** 

**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

#### **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

#### **STYLES ON PAGE 2**

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#### SOIC-8 NB CASE 751-07 ISSUE AK

### DATE 16 FEB 2011

STYLE 4: PIN 1. ANODE 1 2. ANODE 2 3. ANODE 2 4. ANODE 5. ANODE #2 6. ANODE #2 7. ANODE #1 8. COMMON CATHODE
STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 STAGE Vd 7. EMITTER, #1 AGE Vd 8. COLLECTOR, #1
STYLE 12:  1 PIN 1. SOURCE 2 SOURCE 2 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COMMON 6. COLLECTOR, DIE #2 6. COMMON 7. COLLECTOR, DIE #1 6. COMMON 8. COLLECTOR, DIE #1
STYLE 20:  1 PIN 1. SOURCE (N) 2. GATE (N) 2 3. SOURCE (P) 4. GATE (P) 5. DRAIN 2 6. DRAIN 7. DRAIN 1 8. DRAIN
STYLE 24:   PIN 1. BASE     N ANODE/GND   2. EMITTER     N ANODE/GND   3. COLLECTOR/ANODE     UT   5. CATHODE     N ANODE/GND   6. CATHODE     N ANODE/GND   7. COLLECTOR/ANODE     UT   8. COLLECTOR/ANODE
STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND E 5. V_MON E 6. VBULK E 7. VBULK 8. VIN

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## **MECHANICAL CASE OUTLINE**

NOTES 4&5

HIH

TOP VIEW

SIDE VIEW

**BOTTOM VIEW** 

NOTE 6

Е

NOTE 6 B

A1 NOTE 8

0.20 C D

△ 0.10 C D

NOTES 4&5

0.10 C D

8X b NOTES 3&7

**♦** 0.25**№** C A-B D

0.10 C

С

SEATING PLANE





SOIC-8 EP CASE 751AC ISSUE D

**DATE 02 APR 2019** 

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS

- 2. CONTROLLING DIMENSION: MILLING LERS
  3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE
  PROTRUSION SHALL BE 0.004 IN EXCESS OF MAXIMUM MATERIAL CONDITION.

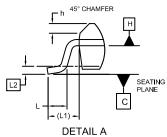
  4. DIMENSION D DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE
  BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED
  0.006 PER SIDE. DIMENSION E1 DOES NOT INCLUDE INTERLEAD FLASH OR
  PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.010 mm PER SIDE.

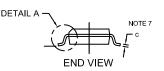
  5. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM.

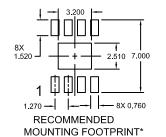
  DIMENSIONS D. AND E1 ADE DETERMINED AT THE OUTERPMOST EYTREMES.
- DIMENSIONS D AND E1 ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 6. DATUMS A AND B ARE TO BE DETERMINED AT DATUM H.
- 8. A1 IS DEFINED AND CAPPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10 TO 0.25 FROM THE LEAD TIP.

  8. A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.









	MILLIMETERS		
DIM	MIN.	NOM	MAX.
Α	1.35	1.55	1.75
A1	İ	0.05	0.10
A2	1.35	1.50	1.65
b	0.31	0.41	0.51
С	0.17	0.21	0.23
D	4.90 BSC		
E	6.00 BSC		
E1	3.90 BSC		
е	1.27 BSC		
F	2.24	2.72	3.20
F1	0.15	0.20	0.25
G	1.55	2.03	2.51
G1	0.41	0.46	0.51
h	0.25	0.38	0.50
L	0.40	0.84	1.27
L1	1.04 REF		
L2	0.25 REF		
Ø	0°	4°	8°

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D."

#### **GENERIC MARKING DIAGRAM\***



XXXXXX = Specific Device Code = Assembly Location Υ = Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present and may be in either location. Some products may not follow the Generic Marking.

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